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Scanning Transmission Electron Microscopy Of Nanomaterials: Basics Of Imaging Analysis
Synopsis
The basics, present status and future prospects of high-resolution scanning transmission electron microscopy (STEM) are described in the form of a textbook for advanced undergraduates and graduate students. This volume covers recent achievements in the field of STEM obtained with advanced technologies such as spherical aberration correction, monochromator, high-sensitivity electron energy loss spectroscopy and the software of image mapping. The future prospects chapter also deals with z-slice imaging and confocal STEM for 3D analysis of nanostructured materials. Readership: Graduate students and researchers in the field of nanomaterials and nanostructures.

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